



Contribution ID: 40

Type: **Lecture**

Information and Imaging, Electrons and Light 1

Friday, 7 June 2024 09:20 (50 minutes)

In electron microscopy, it is crucial to minimize dose in order to prevent electron-induced specimen damage. We will discuss an information theoretical approach to quantifying the information that can be obtained about certain parameters of interest in a given microscope. We will then present results on optical wave-front shaping and optical near-field electron microscopy and will discuss how these techniques can help to reduce damage in electron microscopy.

Presenter: JUFFMANN, Thomas (University of Vienna, Austria)

Session Classification: Lectures

Track Classification: Topics: Optoelectronics and nanophotonics